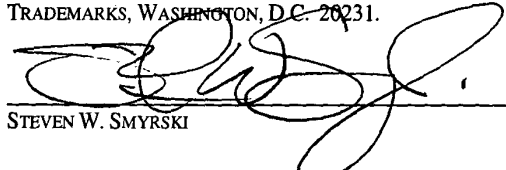




PATENT
Atty Docket No. KLAC0012

#1315
08/19/03

I CERTIFY THAT ON FEBRUARY 19, 2002, WHICH IS THE
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STEVEN W. SMYRSKI

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re application of

CHRISTOPHER FAIRLEY, ET AL.

Title: CONFOCAL WAFER INSPECTION
METHOD AND APPARATUS

Serial No.: 09/533,203

Filed: MARCH 23, 2000

Group Art Unit: 2878

Examiner: Eric J. Spears

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AMENDMENT ACCOMPANYING REQUEST FOR CONTINUED
EXAMINATION (RCE)

Hon. Commissioner of Patents and Trademarks
Washington, D.C. 20231

Sir:

In response to the Office Action dated November 19, 2002, please consider the
following remarks in connection with the above-identified patent application.